

# Advanced statistical methods

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## Part C

### Hypothesis testing - Detection theory

# Part C: Contents

## I. Generalities

- Principles
- Errors, power and level of a test
- Neyman approach

## II. UMP tests

- Simple hypothesis testing
- Composite tests - One-sided hypotheses

## III. Student- $t$ test

## IV. Asymptotic Tests

- Generalities
- Wald test
- Rao (score) test and LRT
- $\chi^2$  tests

# Key references of Part C

From an EE / SP point of view...

- Kay, Steven M. *Fundamentals of Statistical Signal Processing - Detection Theory*, Vol. 2, Prentice Hall, 1998.
- Poor, Vincent, H. *An Introduction to Signal Detection and Estimation*, 2nd ed, Springer, 1998.

From a statistical point of view...

- Lehmann, Erich L., and Romano, Joseph P. *Testing Statistical Hypotheses*, Springer, 2006.
- Casella, George, and Roger L. Berger. *Statistical inference*, Vol. 2. Pacific Grove, CA: Duxbury, 2002.

+ many many references...

## I. Generalities

- Principles
- Errors, power and level of a test
- Neyman approach

## II. UMP tests

## III. Student- $t$ test

## IV. Asymptotic Tests

# Generalities

Let a  $n$ -sample  $(\mathbf{x}_1, \dots, \mathbf{x}_n)$  i.i.d.  $\sim P_\theta, \theta \in \Theta$ . Let  $H_0$  and  $H_1$ , 2 non-empty disjoint subsets of  $\Theta$  s.t.  $H_0 \cup H_1 = \Theta$ .

$H_0$  is the **null hypothesis** while  $H_1$  is called the **alternative hypothesis**.

**Remember: no symmetry!**

**Goal:** To find a procedure that allows to decide whether  $\theta$  belongs to  $H_0$  or not, regarding the datasets  $x = (x_1, \dots, x_n) \in \mathcal{X}^n$ .

## Definition

*An hypothesis is said **simple** if it is reduced to a single element. Else, it is called **composite**.*

## Definition

*A (**pure**) test is a mapping  $\delta$  from  $\mathcal{X}^n$  onto  $\{0, 1\}$  s.t.:*

*If  $\delta(x) = 0$ , one decides  $H_0$ , while if  $\delta(x) = 1$ , one rejects  $H_0$ .*

*The region  $W = \{x \in \mathcal{X}^n \mid \delta(x) = 1\}$  is called the **rejection region** or the **critical region**. Its complement is called the **acceptance region**.*

# Generalities

## Remark

*A test is characterized (and will be identified) by its rejection region  $W$ .*

## Definition (Different errors)

*For a test, there are two possible errors:*

- *rejecting  $H_0$  when it is true: **type-I error or error of 1<sup>st</sup> kind**.*
- *accepting  $H_0$  when it is false: **type-II error or error of 2<sup>nd</sup> kind**.*

## Definition (Type-I and Type-II errors)

*For a test  $\delta$  with critical region  $W$ , one has*

- **Type-I error:**  $\alpha_W: \begin{cases} H_0 \rightarrow [0, 1] \\ \theta \mapsto P_\theta(W); \end{cases}$
- **Type-II error:**  $\beta_W: \begin{cases} H_1 \rightarrow [0, 1] \\ \theta \mapsto P_\theta(W^c) = 1 - P_\theta(W). \end{cases}$

# Generalities

## Definition (**Power of the test**)

The **power** of a test  $W$  is defined as:

$$\rho_W: \begin{cases} H_1 \rightarrow [0, 1] \\ \theta \mapsto P_\theta(W) = 1 - \beta_W(\theta). \end{cases}$$

## Definition (**Randomized test (more general)**)

A random test is a mapping  $\varphi$  from  $\mathcal{X}^n$  into  $[0, 1]$  where  $\varphi(x)$  is the probability of rejecting  $H_0$  for the dataset  $x = (x_1, \dots, x_n) \in \mathcal{X}^n$ .

## Remark

For  $\varphi = \mathbb{1}_W$ , one retrieves the simple test!



# Generalities

## Definition (Type-I and Type-II errors, power for a test $\varphi$ )

- *Type-I error:*  $\alpha_{\varphi} : \begin{cases} H_0 \rightarrow [0, 1] \\ \theta \mapsto E_{\theta} [\varphi(\mathbf{x})]; \end{cases}$
- *Type-II error:*  $\beta_{\varphi} : \begin{cases} H_1 \rightarrow [0, 1] \\ \theta \mapsto 1 - E_{\theta} [\varphi(\mathbf{x})]; \end{cases}$
- *Power of the test:*  $\rho_{\varphi} = 1 - \beta_{\varphi} = E_{H_1} [\varphi(\mathbf{x})].$

## Definition (Level of significance ( $\alpha$ ))

The *level of significance*  $\alpha$  (typically 0.01 or 0.05 as for the IC) for a test  $\varphi$  is:

$$\alpha = \sup_{\theta \in H_0} \alpha_{\varphi}(\theta) = \sup_{\theta \in H_0} E_{\theta} [\varphi(\mathbf{x})].$$

# Neyman Principle

Goal: one wants to control (or fix) the type-I error, i.e. the probability of rejecting  $H_0$  when it is true.

The Neyman principle consists in considering all tests with a  $ls \leq$  to a fixed  $\alpha$ , and then, in finding (among these tests) the one with the smallest Type-II error.

Since  $\rho_\varphi = 1 - \beta_\varphi$ , such test will said to be UMP.

Definition (**Uniformly Most Powerful (UMP)**)

$\varphi$  is UMP at the threshold  $\alpha$  if its  $ls \leq \alpha$  and if  $\forall \varphi'$  with a  $ls \leq \alpha$ , one has:

$$\forall \theta \in H_1, E_\theta [\varphi(\mathbf{x})] \geq E_\theta [\varphi'(\mathbf{x})] .$$

## I. Generalities

## II. UMP tests

- Simple hypothesis testing
- Composite tests - One-sided hypotheses

## III. Student- $t$ test

## IV. Asymptotic Tests

# Simple hypothesis testing

In this part, for the  $n$ -sample  $(\mathbf{x}_1, \dots, \mathbf{x}_n)$ , one considers,

$$H_0 : \{\theta = \theta_0\} \text{ versus } H_1 : \{\theta = \theta_1\},$$

which means that  $\Theta = \{\theta_0, \theta_1\}$ .

So, 2 probabilities  $P_{\theta_0}$  (or  $P_0$ ) and  $P_{\theta_1}$  (or  $P_1$ ), that implies 2 LF  $L_0(x) = L(x; \theta_0)$  and  $L_1(x) = L(x; \theta_1)$ , for  $x = (x_1, \dots, x_n) \in \mathcal{X}^n$ .

**Definition (Neyman test or Likelihood Ratio Test (LRT))**

A Neyman test is a test  $\varphi$  s.t.  $\exists k \in \mathbb{R}_+^*$ , and

$$\varphi(x) = \begin{cases} 1 & \text{if } L(x; \theta_1) > k L(x; \theta_0) \\ 0 & \text{if } L(x; \theta_1) < k L(x; \theta_0) \end{cases}$$

The value of  $\varphi$  is not specified for  $\{x \in \mathcal{X}^n \mid L_1(x) = k L_0(x)\}$ .

# Neyman-Pearson Lemma

## Remark

$L_1(x)/L_0(x)$  is called the **Likelihood Ratio (LR)**. The Neyman test consists in accepting the most likely hypothesis for a given observation  $x$ .

## Proposition (Neyman-Pearson Lemma)

- Existence**  $\forall \alpha \in (0, 1)$ , it exists a Neyman test s.t.  $E_{\theta_0}(\varphi) = \alpha$ .  
Moreover,  $k$  is the quantile of order  $(1 - \alpha)$  of the LR distribution  $\frac{L_1(x)}{L_0(x)}$  under  $P_0$  and one can impose that  $\varphi$  is constant for  $x \in \mathcal{X}^n$  s.t.  $\underline{L_1(x) = kL_0(x)}$ . If the LR CDF under  $P_0$  evaluated in  $k$  is  $(1 - \alpha)$  (**continuous CDF**), thus one can choose this constant = 0 (pure test).
- S. cond.**  $\forall \alpha \in (0, 1)$ , a Neyman test s.t.  $E_{\theta_0}(\varphi) = \alpha$  is **UMP** at level  $\alpha$ .
- N. cond.**  $\forall \alpha \in (0, 1)$ , a UMP test at level  $\alpha$  is **necessarily a Neyman test**.

## Proof

*Essential to built the Neyman test...*

# Neyman-Pearson Lemma

## Remark

- 1 *Conclusion: the only UMP tests at level  $\alpha$  are the Neyman tests of level of significance  $\alpha$ .*
- 2 *If the LR CDF under  $H_0$  is continuous, one obtains the test of critical region  $W = \{x \in \mathcal{X}^n \mid L_1(x) > k L_0(x)\}$  where  $k$  is defined by  $P_0(L_1(X) > k L_0(X)) = \alpha$ .*
- 3 *The power  $E_1(\varphi)$  of a UMP test at level  $\alpha$  is necessarily  $\geq \alpha$ . Indeed,  $\varphi$  is preferable to the constant test  $\psi = \alpha$  (which is of ls  $\alpha$ ), thus  $E_1(\varphi) \geq E_1(\psi) = \alpha$ .*

# Neyman-Pearson Lemma

**Example 1:** Let us consider the exponential model (1)

$$L(x, \theta) = C(\theta) h(x) \exp \left[ \sum_{j=1}^d Q_j(\theta) S_j(x) \right]$$

where  $\theta \in \{\theta_0, \theta_1\}$ , with  $\theta_1 > \theta_0$ . Assume an identifiable model:  
 $Q(\theta_0) \neq Q(\theta_1)$  (e.g.,  $Q(\theta_1) > Q(\theta_0)$ ).

Goal: test  $H_0 : \{\theta = \theta_0\}$  versus  $H_1 : \{\theta = \theta_1\}$ .

**Example 2:** Let us consider  $(X_1, \dots, X_n) \stackrel{iid}{\sim} \mathcal{N}(\mu, \sigma^2)$  with  $\sigma^2$  known.

Goal: test  $H_0 : \{\mu = \mu_0\}$  versus  $H_1 : \{\mu = \mu_1\}$ , with  $\mu_0 < \mu_1$ .

**Example 3:** Let us consider  $(X_1, \dots, X_n) \stackrel{iid}{\sim} \text{Poisson}(\theta)$ .

Goal: test  $H_0 : \{\theta = \theta_0\}$  versus  $H_1 : \{\theta = \theta_1\}$ , with  $\theta_0 < \theta_1$ .

# Composite tests - One-sided hypotheses

Now, let us consider a model with only 1 parameter and where  $\Theta$  is an interval of  $\mathbb{R}$ . One assume  $L(x, \theta) > 0, \forall x \in \mathcal{X}^n, \forall \theta \in \Theta$ .

Goal: test  $H_0 : \{\theta \leq \theta_0\}$  versus  $H_1 : \{\theta > \theta_0\}$ .

More general problem!

Let us consider the family having **monotone likelihood ratio**:

## Definition (**Monotone LR**)

The family  $\{P_{\theta}^{\otimes n}, \theta \in \Theta\}$  is said to have **monotone likelihood ratio** if it exists a real-valued statistic  $U(x)$  s.t.  $\forall \theta' < \theta'', \frac{L(x, \theta'')}{L(x, \theta')}$  is a strictly increasing (or decreasing) function of  $U$ .

## Remark

By changing  $U$  into  $-U$ , one can always assume strictly increasing in previous definition.



# Lehman Theorem

## Theorem (Lehman theorem)

Let  $\alpha \in (0, 1)$ . If the family  $(P_\theta, \theta \in \Theta)$  has **monotone (increasing) likelihood ratio**, there exists a UMP test at level  $\alpha$  for testing  $H_0 : \{\theta \leq \theta_0\}$  versus  $H_1 = \{\theta > \theta_0\}$ . This test is defined by:

$$\begin{cases} \varphi(x) = 1 & \text{if } U(x) > c \\ \varphi(x) = \gamma & \text{if } U(x) = c \\ \varphi(x) = 0 & \text{if } U(x) < c \end{cases}$$

where  $c$  and  $\gamma$  are obtained with  $E_{\theta_0}[\varphi] = \alpha$ . The same test is UMP at level  $\alpha$  for testing:

1  $H_0 : \{\theta = \theta_0\}$  versus  $H_1 : \{\theta > \theta_0\}$

2  $H_0 : \{\theta = \theta_0\}$  versus  $H_1 : \{\theta = \theta_1\}$

where  $\theta_1 > \theta_0$ .

# Lehman Theorem

## Remark

*If the inequalities are reversed in the test, i.e.  $H_0 : \{\theta \geq \theta_0\}$  and  $H_1 : \{\theta < \theta_0\}$ , then the UMP test is obtained by reversing the inequalities (in the test).*

**Example:** The exponential model with LF  $L(x, \theta) = C(\theta)h(x) \exp(Q(\theta)S(x))$  where  $Q(\theta)$  is strictly increasing, has increasing LR with  $U(X) = S(X)$ .

## Remark (Important)

*In general, **it does NOT exist** UMP test for testing  $H_0 : \{\theta = \theta_0\}$  versus  $H_1 : \{\theta \neq \theta_0\}$  (even for monotone LR).*

*For instance, let's consider the Gaussian model,  $\sigma^2$  known. The UMP test for  $H_0 : \{\mu = \mu_0\}$  versus  $H_1 : \{\mu > \mu_0\}$  is  $\begin{cases} \rho(x) = 1 & \text{if } \sum x_i > c \\ \rho(x) = 0 & \text{if } \sum x_i \leq c \end{cases}$  while the*

*UMP test for  $H_0 : \{\mu = \mu_0\}$  versus  $H_1 : \{\mu < \mu_0\}$  is  $\begin{cases} \rho(x) = 1 & \text{if } \sum x_i < c \\ \rho(x) = 0 & \text{if } \sum x_i \geq c \end{cases}$*

*$\Rightarrow$  **no UMP test for testing  $\mu = \mu_0$  versus  $\mu \neq \mu_0$ .***

I. Generalities

II. UMP tests

III. Student- $t$  test

IV. Asymptotic Tests

# Student test

Let  $(X_1, \dots, X_n) \stackrel{iid}{\sim} \mathcal{N}(\mu, \sigma^2)$  with  $\mu$  and  $\sigma^2$  unknown.

**Goal:** test  $H_0 : \{\mu = \mu_0\}$  versus  $H_1 : \{\mu \neq \mu_0\}$  at level  $\alpha \in (0, 1)$ .

## General methodology

- 1 From the *Student theorem*, one has

$$T_n = \frac{\sqrt{n}(\bar{X}_n - \mu)}{S_n} \sim t(n-1)$$

where  $\bar{X}_n = \frac{1}{n} \sum_{i=1}^n X_i$  and  $S_n^2 = \frac{1}{n-1} \sum_{i=1}^n (X_i - \bar{X}_n)^2$ .

- 2 Under  $H_0$ :

$$\xi_n = \frac{\sqrt{n}(\bar{X}_n - \mu_0)}{S_n} \sim t(n-1)$$

- 3 Under  $H_1$ : From the SLLN,  $\bar{X}_n - \mu_0 \xrightarrow[n \rightarrow \infty]{a.s.} \mu - \mu_0$  and  $S_n \xrightarrow[n \rightarrow \infty]{a.s.} \sigma$ .

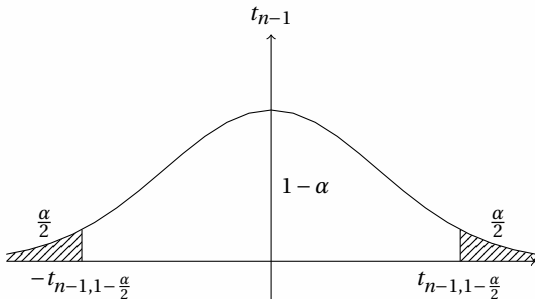
Thus  $\xi \xrightarrow[n \rightarrow \infty]{a.s.} +\infty$  if  $\mu > \mu_0$  and  $\xi \xrightarrow[n \rightarrow \infty]{a.s.} -\infty$  if  $\mu < \mu_0$

- 4 Critical region:

$$\mathbf{W}_n = \{|\xi_n| > \mathbf{a}\}$$

# Student test

- Let  $t_{n-1,r}$  the quantile of order  $r$  of the  $t$ -distribution  $t_{n-1}$ :



Thus, under  $H_0$ ,  $P(|\xi_n| > t_{n-1, 1-\frac{\alpha}{2}}) = \alpha$ .

Previously, one have seen that  $I_n = \left[ \bar{X}_n - \frac{t_{n-1, 1-\alpha/2} S_n}{\sqrt{n}}, \bar{X}_n + \frac{t_{n-1, 1-\alpha/2} S_n}{\sqrt{n}} \right]$  is a  $(1-\alpha)$ -CI for  $\mu_0$ . Here is the link between CI and Student (bilateral) test  $\mu_0 \in I_n$  iff  $|\xi_n| \leq t_{n-1, 1-\frac{\alpha}{2}}$ . Finally, the associated  $p$ -value is  $p = P(|T| > |\xi_n^{obs}|)$  where  $T \sim t(n-1)$  and  $\xi_n^{obs}$  is the observed value of  $\xi_n$ .

I. Generalities

II. UMP tests

III. Student- $t$  test

IV. Asymptotic Tests

- Generalities
- Wald test
- Rao (score) test and LRT
- $\chi^2$  tests

# Generalities

As for estimators, in many situations, one CANNOT find the distribution of the LR (or the statistic of the monotone LR). As a consequence, one cannot set the parameters  $k$  and  $\gamma$  for the test.

A solution (like in point estimation theory) is to rely on asymptotic properties!

Now, instead of considering a test  $W$ , we will consider a sequence of tests  $(W_n)_{n \in \mathbb{N}^*}$ .

## Definition (Asymptotic level)

An asymptotic test  $W_n$  is at **asymptotic level**  $\alpha$  if

$$\lim_{n \rightarrow \infty} \sup_{\theta \in H_0} P_{\theta}(W_n) = \alpha.$$

# Generalities

## Definition (**Uniform asymptotic level**)

An asymptotic test  $W_n$  is at **uniform asymptotic level**  $\alpha$  if

$$\sup_{\theta \in H_0} \lim_{n \rightarrow \infty} P_{\theta}(W_n) = \alpha.$$

## Definition (**Consistant (or convergent) test**)

An asymptotic test  $W_n$  is said to be **consistant (or convergent)** if its power tends towards 1, i.e.,

$$\forall \theta \in H_1, \lim_{n \rightarrow \infty} P_{\theta}(W_n) = 1.$$

*This means that the Type-II error tends to 0!*

**Example:** the  $t$ -test is consistant...



# Asymptotic tests

**Implicit constraint:**  $H_0 : \{\theta | g(\theta) = 0\}$

where  $g$  a mapping from  $\mathbb{R}^d$  into  $\mathbb{R}^r$ , of class  $C^1$  s.t. the  $r \times d$  matrix

$$\frac{\partial g}{\partial \theta^t} = \left( \frac{\partial g_i}{\partial \theta_j} \right)_{1 \leq i \leq r, 1 \leq j \leq d} \text{ is of rank } r \text{ (so } r \leq d \text{)}.$$

Goal: test  $H_0 : \{\theta \in \Theta, g(\theta) = 0\}$  versus the alternative hypothesis  
 $H_1 : \{\theta \in \Theta, g(\theta) \neq 0\}$

**More general than  $H_0 : \{\theta = \theta_0\}$  versus  $H_1 : \{\theta \neq \theta_0\}$**

To answer such problems, there exist (at least) 3 asymptotic tests:

- Wald test
- Rao (score) test
- Likelihood Ratio Test (LRT)

# Wald test

## Proposition (Wald test)

Let  $\hat{\theta}_n^{ML}$  the MLE of  $\theta$ . Under  $H_0$ , the sequence of r.V., one has:  
 $(\sqrt{n}g(\hat{\theta}_n^{ML})) \xrightarrow[n \rightarrow \infty]{dist.} \mathcal{N}(\mathbf{0}, \Sigma(\theta_0))$ , where  $\theta_0 \in H_0$  is the true value of the parameter  $\theta$  and where  $\Sigma(\theta_0) = \frac{\partial g}{\partial \theta^t}(\theta_0) I_1(\theta_0)^{-1} \frac{\partial g^t}{\partial \theta}(\theta_0)$ .

Furthermore, the test statistic  $\xi_n^W = n g(\hat{\theta}_n^{ML})^t \Sigma(\hat{\theta}_n^{ML})^{-1} g(\hat{\theta}_n^{ML})$  converges in distribution under  $H_0$  towards a  $\chi^2$ -distribution with  $r$  d.o.f.:

$$\xi_n^W \xrightarrow[n \rightarrow \infty]{dist.} \chi^2(r)$$

The Wald tests are defined by the following critical region:

$$W_n = \{\xi_n^W > q_r(1 - \alpha)\}$$

where  $q_r(1 - \alpha)$  is the quantile of order  $(1 - \alpha)$  of the  $\chi^2$ -distribution with  $r$  d.o.f. This test is strongly convergent at asymptotic level  $\alpha = P(\chi^2(r) > q_r(1 - \alpha))$ .

# Wald test

## Definition (*p-value*)

The asymptotic *p*-value of the Wald test is defined by

$$p = P(\chi^2(r) > \xi_n^W(x_1, \dots, x_n))$$

where  $\chi^2(r)$  is a r.v. following a  $\chi^2$ -dist. with  $r$  d.o.f. and  $\xi_n^W(x_1, \dots, x_n)$  is the observed test statistic. *One rejects  $H_0$  if  $p < \alpha$ ...*

## Remark

If one cannot compute  $I_1(\theta)$ . One can estimate  $I_1(\theta)$  by the MM and replace it in the Wald test *WITHOUT changing the results!*:

$$\hat{I}_1(\cdot) = \frac{1}{n} \sum_{i=1}^n \frac{\partial \ln L(x_i, \cdot)}{\partial \theta^t} \frac{\partial \ln L(x_i, \cdot)}{\partial \theta}^t \quad \text{ou} \quad \hat{I}_1(\cdot) = -\frac{1}{n} \sum_{i=1}^n \frac{\partial^2 \ln L(x_i, \cdot)}{\partial \theta \partial \theta^t}.$$

## Proof (Wald test)

*Allows to understand the methodology...*

## Wald test

**Example:** Let a Gaussian  $n$ -sample  $\begin{pmatrix} X_i \\ Y_i \end{pmatrix}_{i \in \{1, \dots, n\}} \sim \mathcal{N} \left( \begin{pmatrix} \mu_1 \\ \mu_2 \end{pmatrix}, \begin{pmatrix} \sigma_1^2 & 0 \\ 0 & \sigma_2^2 \end{pmatrix} \right)$  with  $\sigma_1$  and  $\sigma_2$  known. Let  $\theta = \begin{pmatrix} \mu_1 \\ \mu_2 \end{pmatrix}$ .

**Goal: test  $\mu_1 = \mu_2$ , i.e.,  $H_0 : \{\mu_1 - \mu_2 = 0\}$  versus  $H_1 : \{\mu_1 - \mu_2 \neq 0\}$ .**

Let us set  $g(\theta) = \mu_2 - \mu_1$  and show that the Wald test statistic is

$$\xi_n^W = \frac{n(\hat{\mu}_1 - \hat{\mu}_2)^2}{\sigma_1^2 + \sigma_2^2}$$

where  $\hat{\mu}_1 = \frac{1}{n} \sum_{i=1}^n X_i$  and  $\hat{\mu}_2 = \frac{1}{n} \sum_{i=1}^n Y_i$ . One has

$$\xi_n^W \xrightarrow[n \rightarrow \infty]{dist.} \chi^2(1)$$

# Rao-score test and Likelihood Ratio test (LRT)

Let  $\hat{\theta}_n^c$  the MLE of  $\theta$  under the constraint  $g(\theta) = 0$ , i.e. under  $H_0$ .

## Theorem (Rao test and LRT)

The test statistics are defined by:

$$\xi_n^R = \frac{1}{n} \frac{\partial \ln L(x_i, \dots, x_n; \hat{\theta}_n^c)}{\partial \theta^t} I_1(\hat{\theta}_n^c)^{-1} \frac{\partial \ln L(x_i, \dots, x_n; \hat{\theta}_n^c)^t}{\partial \theta}$$
$$\xi_n^{LR} = 2(\ln L(x_i, \dots, x_n; \hat{\theta}_n) - \ln L(x_i, \dots, x_n; \hat{\theta}_n^c))$$

Rao test and the LRT are defined by the following critical region

$$W_n = \{\xi_n^i > q_r(1 - \alpha)\}$$

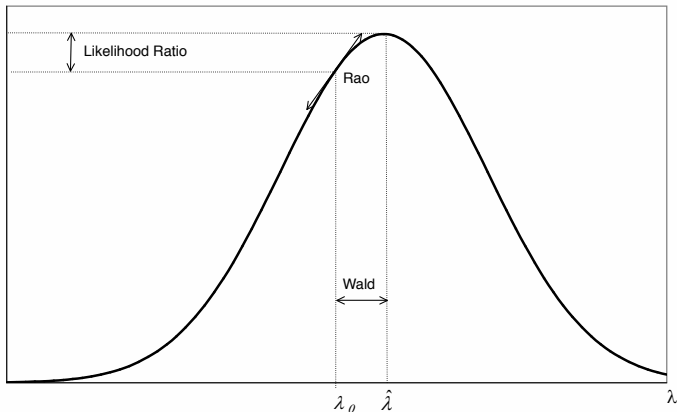
where  $q_r(1 - \alpha)$  is the quantile of order  $(1 - \alpha)$  of the  $\chi^2$ -distribution with  $r$  d.o.f. These tests are strongly convergent at asymptotic level  $\alpha = P(\chi^2(r) > q_r(1 - \alpha))$ . Furthermore, *under  $H_0$* , one has:

$$\xi_n^W - \xi_n^R \xrightarrow[n \rightarrow \infty]{P} 0 \text{ and } \xi_n^W - \xi_n^{LR} \xrightarrow[n \rightarrow \infty]{P} 0$$

# Rao-score test and Likelihood Ratio test (LRT)

**Example** Testing  $H_0 : \{\lambda = \lambda_0\}$  versus  $H_1 : \{\lambda \neq \lambda_0\}$  in case of a Poisson distribution with parameter  $\lambda$ ...

...



# $\chi^2$ test: Goodness-of-Fit to a given distribution

Goal: test the goodness of fit of r.V. to a discrete and finite distribution (e.g., binomial, ...)

Quite restrictive but it CAN be extended to all distributions!

Let the  $n$ -sample  $(X_1, \dots, X_n)$  i.i.d. with values in  $\{a_1, \dots, a_m\}$  and distribution  $P$ , where  $P$  is characterized by its weights  $P = (p_1, \dots, p_m)$  (it is a PMF) with  $\sum_{i=1}^m p_i = 1$  and  $\forall j = 1, \dots, n, \forall i = 1, \dots, m, p_i = P(X_j = a_i)$ .

One wants to test  $H_0 : \{P = P_{p_0}\}$ , where  $p_0 = (p_1^0, \dots, p_m^0)$  is given (no unknown parameter) with  $\sum_{i=1}^m p_i^0 = 1, p_i^0 > 0, \forall i = 1, \dots, m$ .

Let  $N_i$  the counting statistic and  $p_i$  is the empirical frequency of  $\{X_k = a_i\}$ :

$$N_i = \sum_{k=1}^n \mathbb{1}_{\{X_k = a_i\}} \quad \text{and} \quad \hat{p}_i = \frac{N_i}{n}$$

# $\chi^2$ test: Goodness-of-Fit to a given distribution

## Theorem ( $\chi^2$ - test)

*Under  $H_0$*

$$\xi_n = \sum_{i=1}^m \frac{(N_i - np_i^0)^2}{np_i^0} = n \sum_{i=1}^m \frac{(\hat{p}_i - p_i^0)^2}{p_i^0}$$

*And  $\xi_n$  converges in distribution towards a  $\chi^2$ -distribution with  $(m-1)$  d.o.f. when  $n \rightarrow +\infty$ .*

*The test is defined by the critical region:*

$$W_n = \{\xi_n > q_{m-1}(1-\alpha)\}$$

*where  $q_{m-1}(1-\alpha)$  is the quantile of order  $(1-\alpha)$  of the  $\chi^2$ -distribution with  $(m-1)$  d.o.f. This test is strongly convergent at asymptotic level  $\alpha = P(\chi^2(m-1) > q_{m-1}(1-\alpha))$ .*

**Example:** Toss a coin...



## $\chi^2$ test: Goodness-of-Fit to a given distribution

Now, let us test  $H_0 : \{p = p(\theta)\}$  versus  $H_1 : \{p \neq p(\theta)\}$  where  $\theta \in \Theta \subset \mathbb{R}^d$ ,  $\Theta$  open-set and  $\theta$  is unknown!

### Theorem (General $\chi^2$ - test)

*Under  $H_0$*

$$\xi_n = \sum_{i=1}^m \frac{(N_i - np_i(\hat{\theta}_n))^2}{np_i(\hat{\theta}_n)} = n \sum_{i=1}^m \frac{(\hat{p}_i - p_i(\hat{\theta}_n))^2}{p_i(\hat{\theta}_n)}$$

where  $\hat{\theta}_n$  is the MLE of  $\theta$ .

And  $\xi_n$  converges in distribution towards a  $\chi^2$ -distribution with  $(m-1-d)$  d.o.f. when  $n \rightarrow +\infty$ .

The test is defined by the critical region:

$$W_n = \{\xi_n > q_{m-1-d}(1-\alpha)\}$$

where  $q_{m-1-d}(1-\alpha)$  is the quantile of order  $(1-\alpha)$  of the  $\chi^2$ -distribution with  $(m-1-d)$  d.o.f. This test is strongly convergent at asymptotic level  $\alpha = P(\chi^2(m-1-d) > q_{m-1-d}(1-\alpha))$ .

# $\chi^2$ test: Goodness-of-Fit to a given distribution

How to generalize those  $\chi^2$  tests to continuous distribution or infinite discrete distribution?

## Remark (On the use of $\chi^2$ tests!)

- It is an *asymptotic* test. In practice, it works if  $np_i(\hat{\theta}_n) > 5, \forall i$  and if  $N_i \geq 5, \forall i$ . Else, one regroups classes (cf exercise in the problems).
- In case of continuous r.v. with unknown distribution, one wants to test if it belongs to the family  $\{P_\theta, \theta \in \Theta\}$ . The idea is to partition  $\mathbb{R}$  into  $m$  intervals  $(A_i)_{i=1,\dots,m}$ . The choice of  $m$  is a tradeoff:
  - $m$  should be sufficiently large so that the discrete dist.  $\{\pi_i = \pi(A_i)\}$  and  $\{p_{\theta,i} = P_\theta(A_i)\}$  be sufficiently close to  $\pi$  and  $P_\theta$  (if  $m$  is small, the test will be less powerful).
  - On the other hand,  $m$  should not be too large so that the  $p_{\theta,i}$  be sufficiently large to satisfy  $np_i(\hat{\theta}_n) > 5$ .

## $\chi^2$ test for independence

Let  $(X_k, Y_k), k = 1, \dots, n$  i.i.d. with values in  $\{a_1, \dots, a_l\} \times \{b_1, \dots, b_r\}$ . Let us denote  $p_{i,j} = P(X_1 = a_i, Y_1 = b_j)$  and

$$p_{i,\cdot} = P(X_1 = a_i) = \sum_{j=1}^r p_{i,j} \text{ and } p_{\cdot,j} = P(Y_1 = b_j) = \sum_{i=1}^l p_{i,j}$$

One wants to know if  $X_1$  and  $Y_1$  are independent, i.e. if

$$H_0 : \{p_{i,j} = p_{i,\cdot} p_{\cdot,j}, \forall i, j\}$$

Let  $N_{i,j} = \sum_{k=1}^n \mathbb{1}_{\{X_k=a_i, Y_k=b_j\}}$  the counting statistic and

$$N_{i,\cdot} = \sum_{k=1}^n \mathbb{1}_{\{X_k=a_i\}} \text{ and } N_{\cdot,j} = \sum_{k=1}^n \mathbb{1}_{\{Y_k=b_j\}}$$

# $\chi^2$ test for independence

## Theorem ( $\chi^2$ - test for independence)

*Under  $H_0$*

$$\xi_n = \sum_{i=1}^l \sum_{j=1}^r \frac{\left( N_{i,j} - \frac{N_{i,\cdot} N_{\cdot,j}}{n} \right)^2}{\frac{N_{i,\cdot} N_{\cdot,j}}{n}}$$

*And  $\xi_n$  converges in distribution towards a  $\chi^2$ -distribution with  $(r-1)(l-1)$  d.o.f.*

*The test is defined by the critical region:*

$$W_n = \{ \xi_n > q_{(r-1)(l-1)}(1-\alpha) \}$$

*where  $q_{(r-1)(l-1)}(1-\alpha)$  is the quantile of order  $(1-\alpha)$  of the  $\chi^2$ -distribution with  $(r-1)(l-1)$  d.o.f. This test is strongly convergent at asymptotic level  $\alpha = P(\chi^2((r-1)(l-1)) > q_{(r-1)(l-1)}(1-\alpha))$ .*

## $\chi^2$ test for independence

**Example** A study on 592 women: is there a correlation between eyes color and hairs color?

Eyes \ Hairs	Hairs			
	Dark	Light-brown	Red	Blond
Black	68	119	26	7
Brown	15	54	14	10
Green	5	29	14	16
Blue	20	84	17	94

One obtains  $\xi_n = 138,29$ ,  $dof = 9$ ,  $P(\chi^2_9 \leq 16,91) = 0,95$ . Since  $138,29 \gg 16,91$ , one rejects  $H_0$ .